

Micro Uniformity Ad-hoc Group Meeting, Sept 19, 2003 1:30PM EDT

(Tele)present: Robert Zeman (Chair, Kodak), William Kress (Toshiba), Rene Rasmussen(Xerox)

An update of this W1.1 standard effort has been accepted to the SPIE conference in January, and the manuscript is due on Oct. 27th. It is somewhat unlikely that any results from measurements can be included in that manuscript, but they may be added at the conference presentation. The presentations will be about 10 minutes long.

RR mentioned that he has samples representing 14 printer systems. He has started scanning using the drum scanner. He has found that for some printer systems, it is not possible to find even 1 square inch (out of an 8" x 10" area), which is free from macro defects. We will nevertheless have to pick the best possible site and filter what we can to enable measuring the microuniformity properties. RR will use the incorporated ruler to designate his choice for the best micro-area and mail the samples for "agreement" to the other group members. Because the one square inch area will eventually need to be cut out for viewing purposes, the overall 8.5" x 11" sample will then be not useful for macro uniformity measurements and so RR is requesting that at least two samples of each single target be printed.

There was some discussion about what "aperture" will be used for the microuniformity measurement. WK stated that as long as we measure, for example, a power spectrum out to 10-12 cy/mm, we can compute for any aperture or eye function. RR agreed and we all also agreed to review visual transfer functions to make suggestions for next time. WK recommended that the VTF be kept flat as it approaches zero, so that the DC term is included. RR said that a roll-off is probably more important for macro measurements. RZ believes that a separate DC measurement may be necessary, because macro low frequency power will swamp the high frequency noise measurements. There was no discussion of phase information, which we previously stated might be important for characterizing some of the artifacts. At this point, however, we are just trying to obtain some agreement of simple measurements across the various devices to see if we're in the same ballpark.

RR mentioned that putting the data on a server still makes the most sense, as opposed to writing CDs or DVDs. RZ has since confirmed with Eric Zeise that no help in this regard will be forthcoming from a higher point in the organization. RR said that given this were true, he might be able to provide a server with 200GB or so for data storage.

Next Teleconference: 1:30PM (EDT), Oct 10, 2003, Ph: 1-888-590-2286; passcode: 35683#

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